

## Maximum Ratings @T<sub>A</sub> = 25°C unless otherwise specified

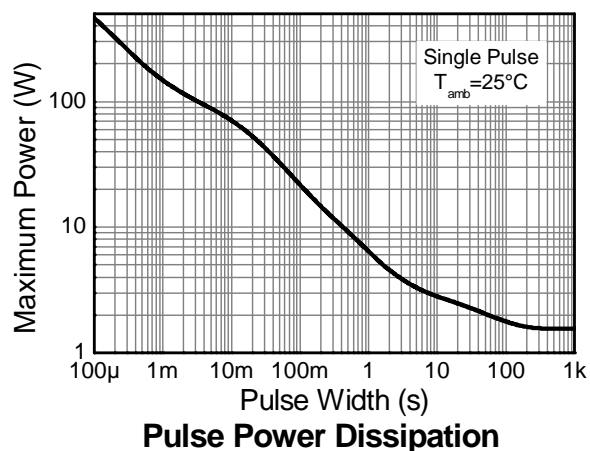
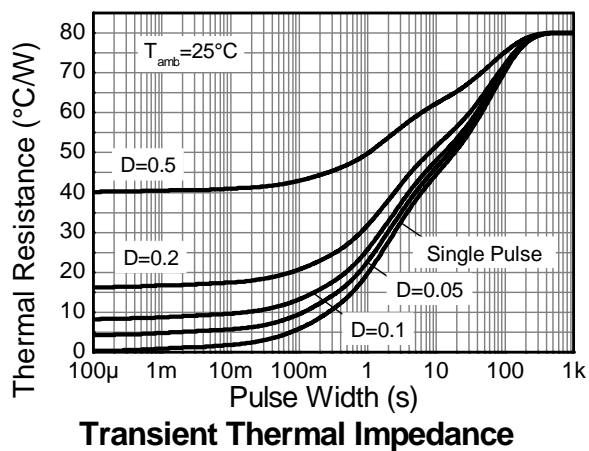
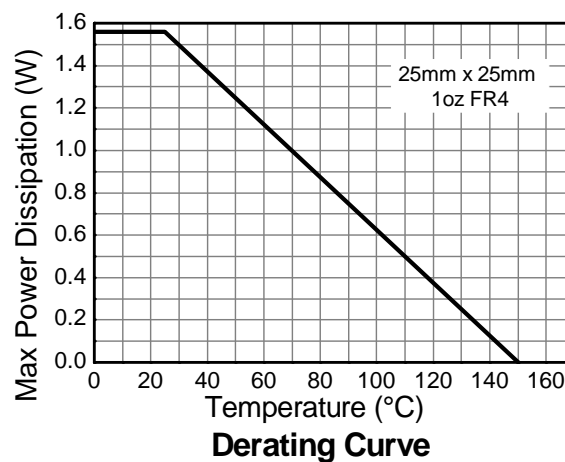
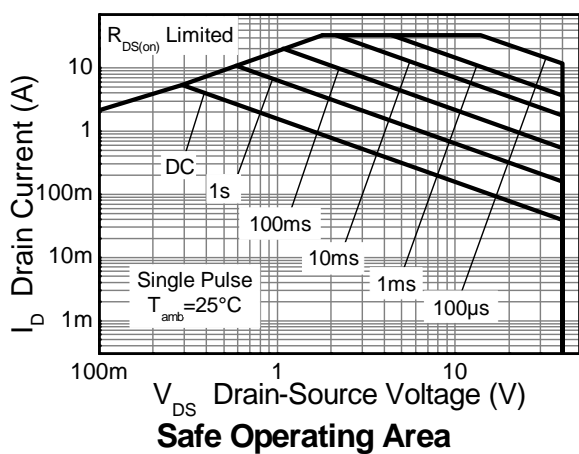
Characteristic			Symbol	Value	Unit
Drain-Source voltage			V <sub>DSS</sub>	40	V
Gate-Source voltage	(Note 2)		V <sub>GS</sub>	±20	V
Single Pulsed Avalanche Energy	(Note 7)		E <sub>AS</sub>	27	mJ
Single Pulsed Avalanche Current	(Note 7)		I <sub>AS</sub>	15.25	A
Continuous Drain current	V <sub>GS</sub> = 10V	(Note 4)	I <sub>D</sub>	7.2	A
		T <sub>A</sub> = 70°C (Note 4)		5.8	
		(Note 3)		5.4	
Pulsed Drain current	V <sub>GS</sub> = 10V	(Note 5)	I <sub>DM</sub>	33.0	A
Continuous Source current (Body diode)		(Note 4)	I <sub>S</sub>	4.1	A
Pulsed Source current (Body diode)		(Note 5)	I <sub>SM</sub>	33.0	A

## Thermal Characteristics @T<sub>A</sub> = 25°C unless otherwise specified

Characteristic		Symbol	Value	Unit
Power dissipation	(Note 3)	P <sub>D</sub>	1.56	W
Linear derating factor	(Note 4)		12.5	
			2.8	
			22.5	mW/°C
Thermal Resistance, Junction to Ambient	(Note 3)	R <sub>θJA</sub>	80	
	(Note 4)		44.5	
Thermal Resistance, Junction to Lead	(Note 6)	R <sub>θJL</sub>	37	°C/W
Operating and storage temperature range		T <sub>J</sub> , T <sub>STG</sub>	-55 to 150	°C

- Notes:
- AEC-Q101 V<sub>GS</sub> maximum is ±16V.
  - For a device surface mounted on 25mm x 25mm x 1.6mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions; the device is measured when operating in a steady-state condition.
  - Same as note (3), except the device is measured at t ≤ 10 sec.
  - Same as note (3), except the device is pulsed with D = 0.02 and pulse width 300μs. The pulse current is limited by the maximum junction temperature.
  - Thermal resistance from junction to solder-point (at the end of the drain lead).
  - UIS in production with L = 100μH, V<sub>DD</sub> = 40V.

## Thermal Characteristics

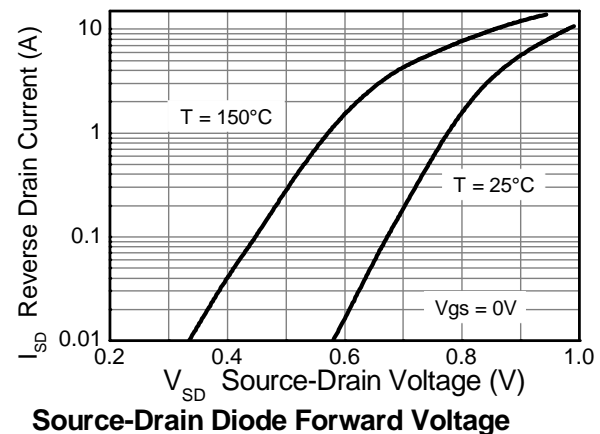
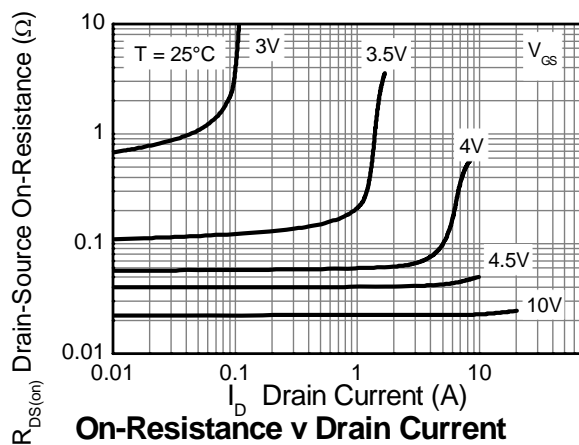
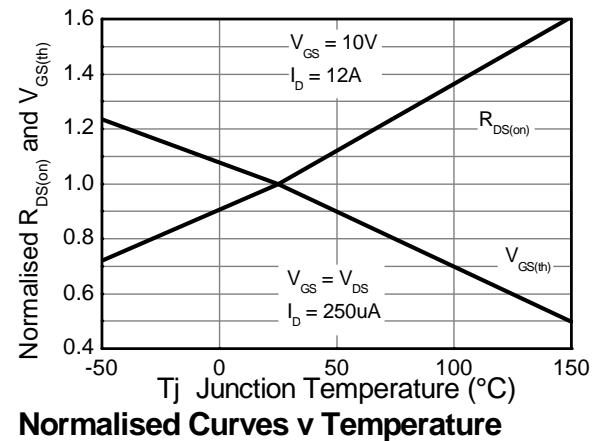
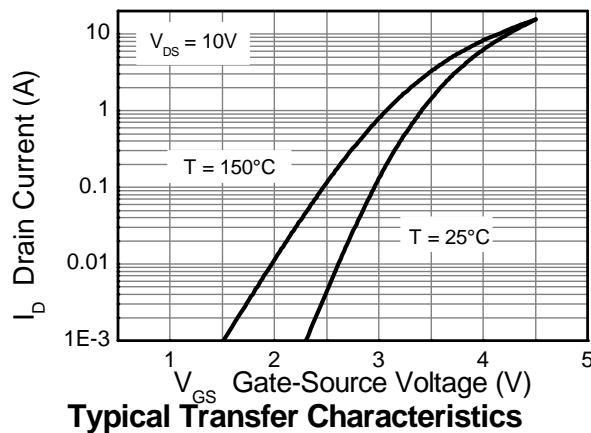
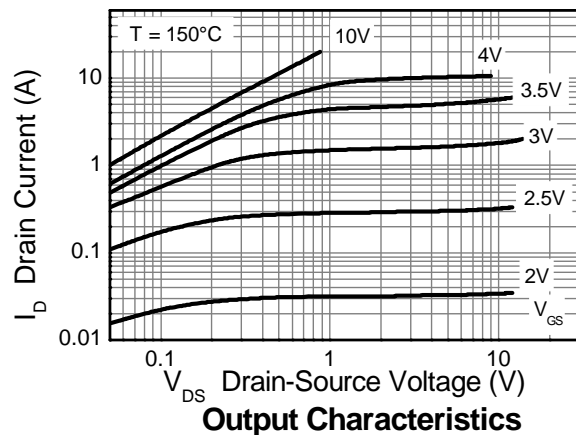
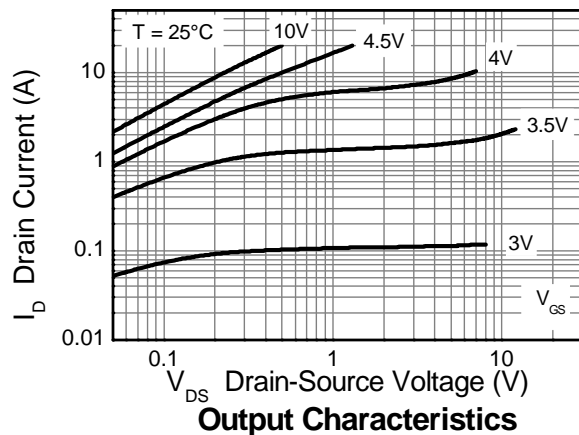


## Electrical Characteristics @T<sub>A</sub> = 25°C unless otherwise specified

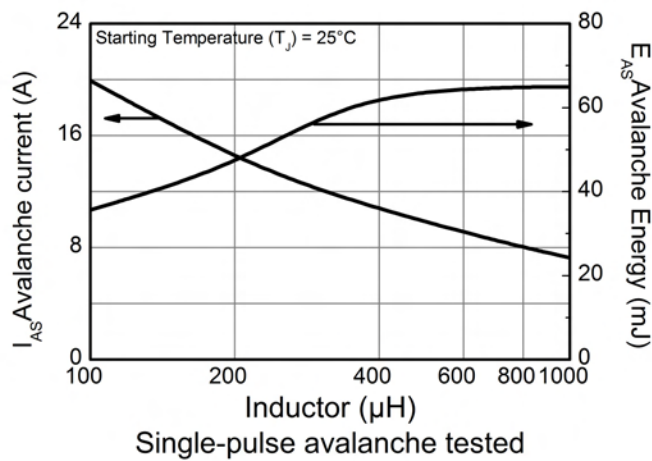
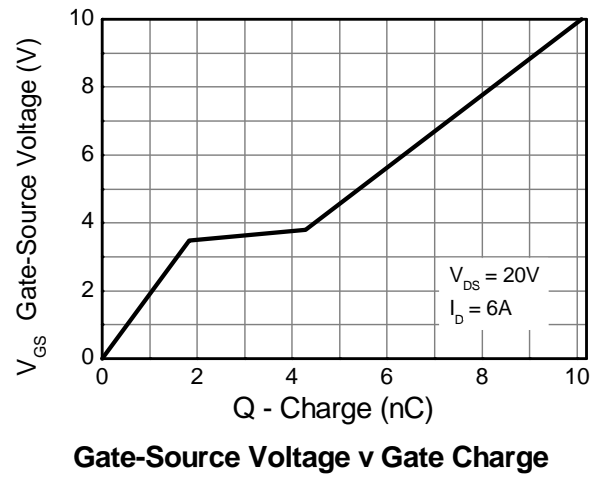
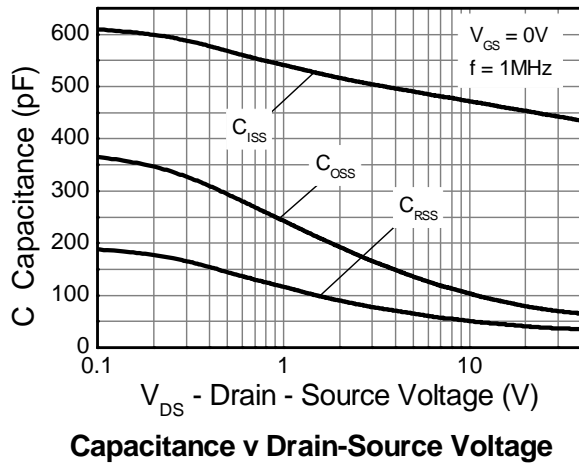
Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition	
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	40	—	—	V	I <sub>D</sub> = 250μA, V <sub>GS</sub> = 0V	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	—	—	1	μA	V <sub>DS</sub> = 40V, V <sub>GS</sub> = 0V	
Gate-Source Leakage	I <sub>GSS</sub>	—	—	±100	nA	V <sub>GS</sub> = ±20V, V <sub>DS</sub> = 0V	
ON CHARACTERISTICS							
Gate Threshold Voltage	V <sub>GS(th)</sub>	1.0	—	3.0	V	I <sub>D</sub> = 250μA, V <sub>DS</sub> = V <sub>GS</sub>	
Static Drain-Source On-Resistance (Note 8)	R <sub>DS (ON)</sub>	—	0.023	0.034	Ω	V <sub>GS</sub> = 10V, I <sub>D</sub> = 6A	
			0.039	0.059		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 5A	
Forward Transconductance (Notes 8 & 9)	g <sub>fs</sub>	—	20.5	—	S	V <sub>DS</sub> = 15V, I <sub>D</sub> = 6A	
Diode Forward Voltage (Note 8)	V <sub>SD</sub>	—	0.87	1.1	V	I <sub>S</sub> = 6A, V <sub>GS</sub> = 0V	
Reverse recovery time (Note 9)	t <sub>rr</sub>		11.9	—	ns	I <sub>S</sub> = 2.5A, di/dt = 100A/μs	
Reverse recovery charge (Note 9)	Q <sub>rr</sub>	—	4.9	—	nC		
DYNAMIC CHARACTERISTICS (Note 9)							
Input Capacitance	C <sub>iSS</sub>	—	453	—	pF	V <sub>DS</sub> = 20V, V <sub>GS</sub> = 0V f = 1MHz	
Output Capacitance	C <sub>oSS</sub>	—	79.1	—	pF		
Reverse Transfer Capacitance	C <sub>rSS</sub>	—	40.5	—	pF		
Total Gate Charge (Note 10)	Q <sub>g</sub>	—	4.9	8	nC	V <sub>GS</sub> = 4.5V	V <sub>DS</sub> = 20V I <sub>D</sub> = 6A
Total Gate Charge (Note 10)	Q <sub>g</sub>	—	10	18	nC	V <sub>GS</sub> = 10V	
Gate-Source Charge (Note 10)	Q <sub>gs</sub>	—	1.8	—	nC		
Gate-Drain Charge (Note 10)	Q <sub>gd</sub>	—	2.4	—	nC		
Turn-On Delay Time (Note 10)	t <sub>D(on)</sub>	—	2.7	—	ns	V <sub>DD</sub> = 20V, V <sub>GS</sub> = 10V I <sub>D</sub> = 1A, R <sub>G</sub> ≅ 6.0Ω	
Turn-On Rise Time (Note 10)	t <sub>r</sub>	—	2.7	—	ns		
Turn-Off Delay Time (Note 10)	t <sub>D(off)</sub>	—	14	—	ns		
Turn-Off Fall Time (Note 10)	t <sub>f</sub>	—	6	—	ns		

- Notes:
8. Measured under pulsed conditions. Pulse width ≤ 300μs; duty cycle ≤ 2%
  9. For design aid only, not subject to production testing.
  10. Switching characteristics are independent of operating junction temperatures.

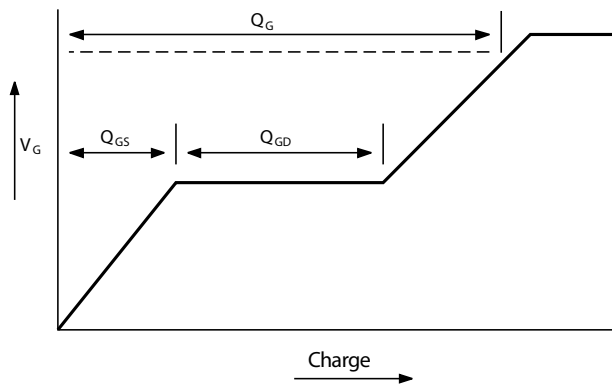
## Typical Characteristics



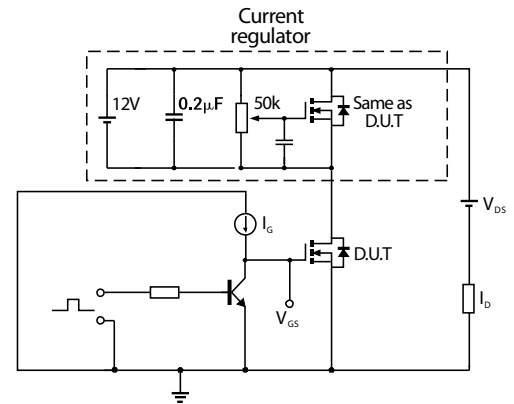
## Typical Characteristics – continued



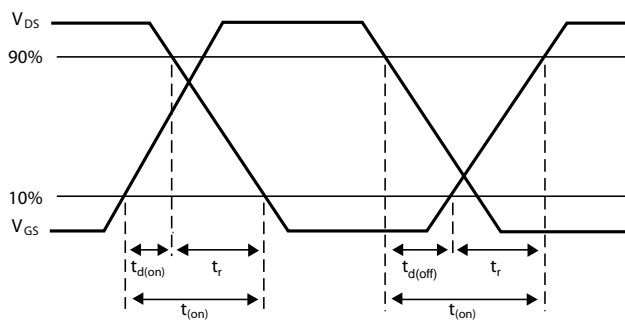
## Test Circuits



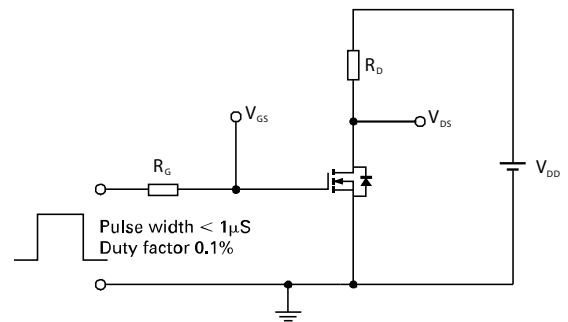
**Basic gate charge waveform**



**Gate charge test circuit**

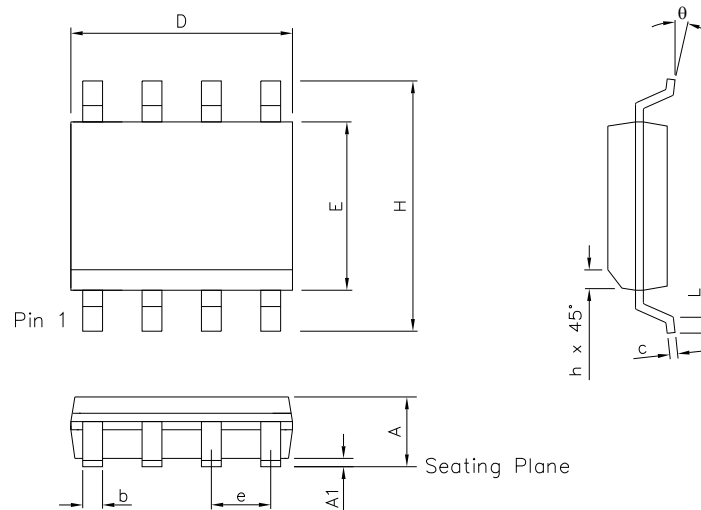


**Switching time waveforms**



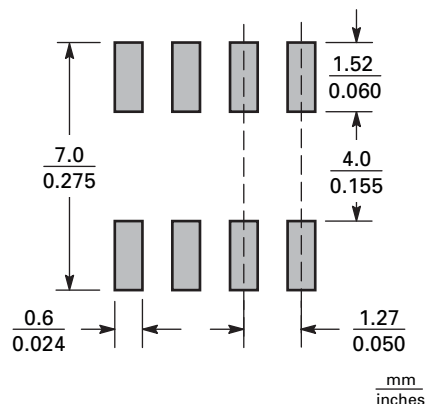
**Switching time test circuit**

## Package Outline Dimensions



DIM	Inches		Millimeters		DIM	Inches		Millimeters	
	Min.	Max.	Min.	Max.		Min.	Max.	Min.	Max.
A	0.053	0.069	1.35	1.75	e	0.050 BSC		1.27 BSC	
A1	0.004	0.010	0.10	0.25	b	0.013	0.020	0.33	0.51
D	0.189	0.197	4.80	5.00	c	0.008	0.010	0.19	0.25
H	0.228	0.244	5.80	6.20	θ	0°	8°	0°	8°
E	0.150	0.157	3.80	4.00	h	0.010	0.020	0.25	0.50
L	0.016	0.050	0.40	1.27	-	-	-	-	-

## Suggested Pad Layout



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